

10/588605

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PATENT

Copies of the foreign search reports are attached for the Examiner's information. Please note this is a PCT application in the entry of the National Phase in the U.S. and copies of the references cited were transmitted by WIPO and are believed to be in the file of the above identified application and readily available to the Examiner. Therefore it is

AP20 Rec'd PCT/PTO 07 AUG 2006

believed that Applicants have met all requirements regarding duty of disclosure under 37 CFR 1.56. Acknowledgement and consideration of these documents are respectfully requested.

Please note this is a PCT application in the entry of the National Phase in the U.S. However, to ensure that these references are available to the Examiner, we are providing copies of these references herewith. Since the Search Reports were from the JPO and EPO search authorities, copies of these references should have been supplied to the USPTO under the trilateral agreement and are believed to be in the file of the above identified application and readily available to the Examiner.

Respectfully submitted,

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INFORMATION DISCLOSURE

CITATION IN AN
APPLICATION

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APPLICANT

Tohru SAITOH, et al.

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August 07, 2006

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U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
/A.H./		US 2002/0130311 A1	09/19/2002	Lieber et al.	Corresponds to JP 2004-507104
/A.H./		US 2002/0163079 A1	11/07/2002	Awano	
/A.H./		US 2003/0089899 A1	05/15/2003	Lieber et al.	
/A.H./		US 2004/0005723 A1	01/08/2004	Empedocles et al.	
/A.H./		US 2005/0142766 A1	06/30/2005	Hareland et al.	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number + Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No
/A.H./		JP 2004-507104	03/04/2004	PRESIDENT AND FELLOWS OF HARVARD COLLEGE	Corresponds to US 2002/0130311 A1	English Abstract Only
/A.H./		JP 2005-510711	04/21/2005	SONY INTERNATIONAL	Corresponds to WO 03/046536 A1	English Abstract Only
/A.H./		WO 03/046536 A1	06/05/2003	SONY INTERNATIONAL	Corresponds to JP 2005-510711	English Abstract Only
/A.H./		WO 2004/032191 A2	04/15/2004	NANOSYS, INC.		English Abstract Only
/A.H./		WO 2004/032193 A2	04/15/2004	NANOSYS, INC.		English Abstract Only
/A.H./		WO 02/080280 A1	10/10/2002	THE REGENTS OF THE UNIVERSITY OF CALIFORNIA		English Abstract Only

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
/A.H./		Duan, X., et al. "High-Performance Thin-Film Transistors Using Semiconductor Nanowires and Nanoribbons," Nature, Vol. 425, September 18 2003, pp. 274-278.
/A.H./		Chen, X., et al. "Electron Mobility Enhancement in Strained SiGe Vertical n-type Metal-oxide-semiconductor Field-effect Transistors," American Institute of Physics, Vol. 78, No. 3, January 15, 2001, pp. 377-379.

EXAMINER

/Andy Huynh/ (04/02/2009)

DATE CONSIDERED

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.